

<b>Notice of References Cited</b>	Application/Control No. 10/637,171	Applicant(s)/Patent Under Reexamination AMARU ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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